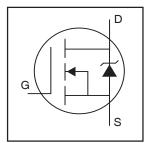
# International Rectifier

# IRF2807PbF

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free



$$V_{DSS} = 75V$$
 $R_{DS(on)} = 13m\Omega$ 
 $I_D = 82A$ 

### **Description**

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



### **Absolute Maximum Ratings**

82⑦ 58 280	А
	Α
280	1
	1
230	W
1.5	W/°C
± 20	V
43	Α
23	mJ
5.9	V/ns
-55 to + 175	
	°C
300 (1.6mm from case )	
10 lbf•in (1.1N•m)	
	1.5 ± 20 43 23 5.9 -55 to + 175 300 (1.6mm from case )

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.65	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	75			V	$V_{GS} = 0V, I_D = 250\mu A$
Breakdown Voltage Temp. Coefficient		0.074		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
Static Drain-to-Source On-Resistance			13	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 43A ④
Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
Forward Transconductance	38			S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 43A④
Drain-to-Source Leakage Current			25	μА	$V_{DS} = 75V, V_{GS} = 0V$
			250		$V_{DS} = 60V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
Gate-to-Source Forward Leakage			100	nΛ	V <sub>GS</sub> = 20V
Gate-to-Source Reverse Leakage			-100	IIA	V <sub>GS</sub> = -20V
Total Gate Charge			160		$I_D = 43A$
Gate-to-Source Charge			29	nC	$V_{DS} = 60V$
Gate-to-Drain ("Miller") Charge			55		$V_{GS} = 10V$ , See Fig. 6 and 13
Turn-On Delay Time		13			$V_{DD} = 38V$
Rise Time		64		no	$I_D = 43A$
Turn-Off Delay Time		49		115	$R_G = 2.5\Omega$
Fall Time		48			$V_{GS} = 10V$ , See Fig. 10 $\textcircled{4}$
Internal Drain Industrance		15			Between lead,
Internal Drain Inductance		4.5		,u	6mm (0.25in.)
Internal Source Inductance		7.5			from package
					and center of die contact
Input Capacitance		3820			$V_{GS} = 0V$
Output Capacitance		610			$V_{DS} = 25V$
Reverse Transfer Capacitance		130		pF	f = 1.0MHz, See Fig. 5
Single Pulse Avalanche Energy <sup>②</sup>		1280 ଔ	340⑥	mJ	I <sub>AS</sub> = 50A, L = 370μH
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance  Drain-to-Source Leakage Current  Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance  Internal Source Inductance  Input Capacitance Output Capacitance Reverse Transfer Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance  Drain-to-Source Leakage Current  Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance  Internal Source Inductance  Reverse Transfer Capacitance  —  Toefficient	Drain-to-Source Breakdown Voltage  Breakdown Voltage Temp. Coefficient  Static Drain-to-Source On-Resistance  Gate Threshold Voltage  Forward Transconductance  Drain-to-Source Leakage Current  Gate-to-Source Forward Leakage  Gate-to-Source Reverse Leakage  Total Gate Charge  Gate-to-Drain ("Miller") Charge  Turn-On Delay Time  Turn-Off Delay Time  Fall Time  January 13  Internal Drain Inductance  Drain-to-Source Inductance  A.5  Internal Source Inductance  Output Capacitance  D.0.074  7.5  1.0.074  0.0074	Drain-to-Source Breakdown Voltage         75         —           Breakdown Voltage Temp. Coefficient         —         0.074         —           Static Drain-to-Source On-Resistance         —         —         13           Gate Threshold Voltage         2.0         —         4.0           Forward Transconductance         38         —         —           Drain-to-Source Leakage Current         —         25           Gate-to-Source Leakage Current         —         —         25           Gate-to-Source Forward Leakage         —         —         100           Gate-to-Source Reverse Leakage         —         —         160           Gate-to-Source Charge         —         —         29           Gate-to-Source Charge         —         —         29           Gate-to-Drain ("Miller") Charge         —         —         55           Turn-On Delay Time         —         13         —           Rise Time         —         64         —           Turn-Off Delay Time         —         48         —           Internal Drain Inductance         —         4.5         —           Internal Source Inductance         —         7.5         —	Drain-to-Source Breakdown Voltage         75         —         —         V           Breakdown Voltage Temp. Coefficient         —         0.074         —         V/°C           Static Drain-to-Source On-Resistance         —         —         13         mΩ           Gate Threshold Voltage         2.0         —         4.0         V           Forward Transconductance         38         —         —         S           Drain-to-Source Leakage Current         —         25         μA           Gate-to-Source Forward Leakage         —         —         100         nA           Gate-to-Source Reverse Leakage         —         —         160         nA           Total Gate Charge         —         —         160         nC           Gate-to-Source Charge         —         —         29         nC           Gate-to-Drain ("Miller") Charge         —         —         55           Turn-On Delay Time         —         13         —           Rise Time         —         49         —           Fall Time         —         48         —           Internal Drain Inductance         —         7.5         —           Internal Source Inductance

### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current			000		MOSFET symbol	
	(Body Diode)			820	82⑦	A	showing the
I <sub>SM</sub>	Pulsed Source Current			280	] ^	integral reverse	
	(Body Diode)①				280		p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.2	V	$T_J = 25^{\circ}C$ , $I_S = 43A$ , $V_{GS} = 0V$ ④	
t <sub>rr</sub>	Reverse Recovery Time		100	150	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 43A	
Q <sub>rr</sub>	Reverse Recovery Charge		410	610	nC	di/dt = 100A/µs ④	
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )					

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\begin{tabular}{ll} \hline @ Starting $T_J = 25^\circ C$, $L = 370\mu H$ \\ $R_G = 25\Omega$, $I_{AS} = 43A$, $V_{GS} = 10V$ (See Figure 12) \\ \hline \end{tabular}$
- $\label{eq:loss} \begin{array}{l} \mbox{ } 3 \mbox{ } I_{SD} \leq 43A, \mbox{ } di/dt \leq 300A/\mu s, \mbox{ } V_{DD} \leq V_{(BR)DSS}, \\ \mbox{ } T_{J} \leq 175^{\circ} \mbox{C} \end{array}$
- 4 Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- 6 This is a calculated value limited to  $T_J = 175^{\circ}C$ .
- ② Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.

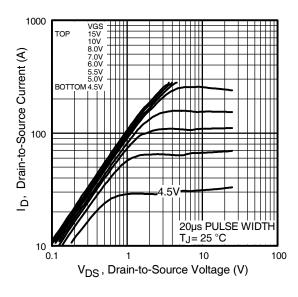


Fig 1. Typical Output Characteristics

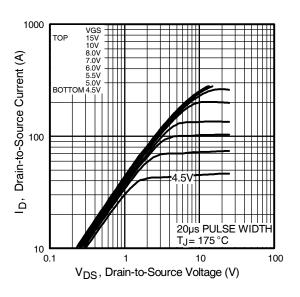


Fig 2. Typical Output Characteristics

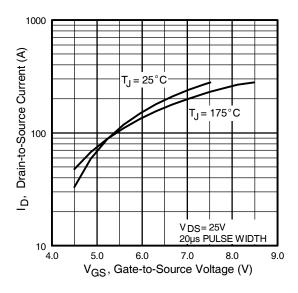
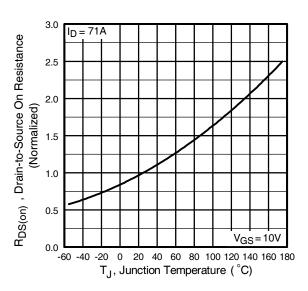
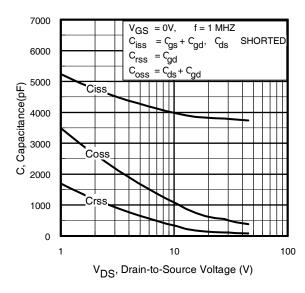


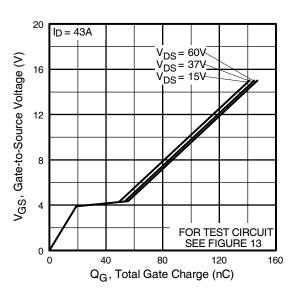
Fig 3. Typical Transfer Characteristics



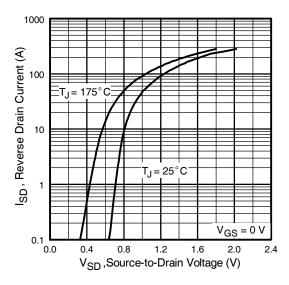
**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

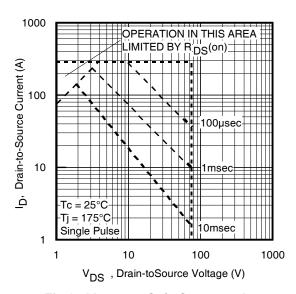
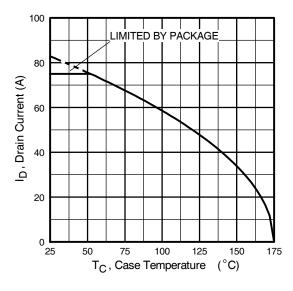


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

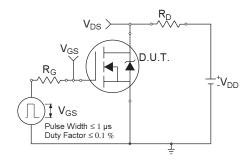


Fig 10a. Switching Time Test Circuit

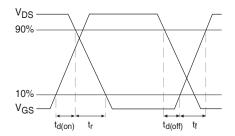


Fig 10b. Switching Time Waveforms

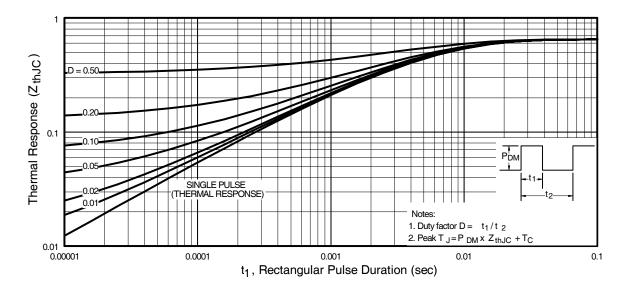


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

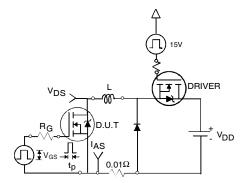


Fig 12a. Unclamped Inductive Test Circuit

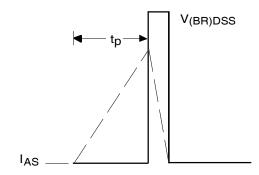


Fig 12b. Unclamped Inductive Waveforms

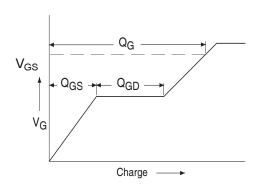


Fig 13a. Basic Gate Charge Waveform

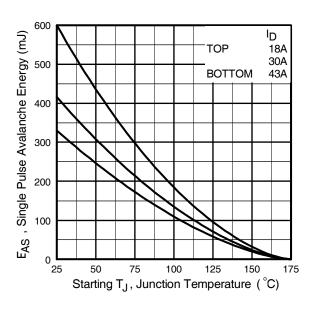


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

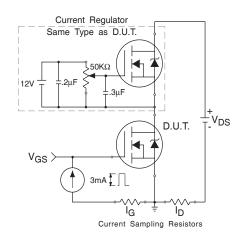
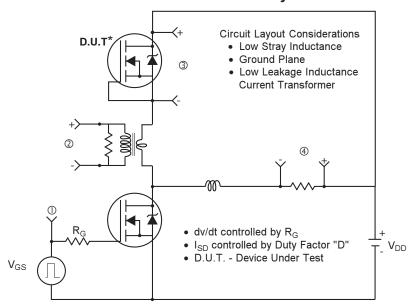
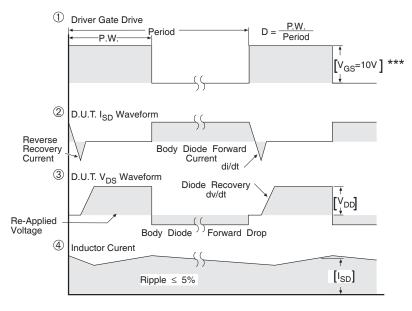


Fig 13b. Gate Charge Test Circuit

### Peak Diode Recovery dv/dt Test Circuit



\* Reverse Polarity of D.U.T for P-Channel



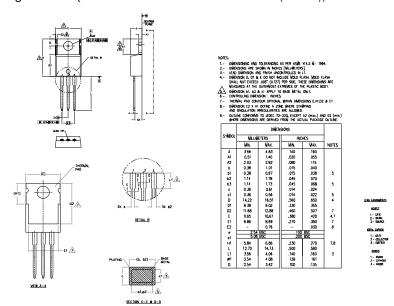
\*\*\*  $V_{GS}$  = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

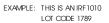
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TO-220AB Package Outline(Dimensions are shown in millimeters (inches))

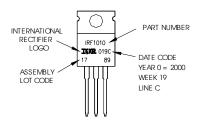


### **TO-220AB Part Marking Information**



ASSEMBLED ON WW 19, 2000 IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead - Free"



TO-220AB package is not recommended for Surface Mount Application.

#### Notes:

8

- 1. For an Automotive Qualified version of this part please see <a href="http://www.irf.com/product-info/auto/">http://www.irf.com/product-info/auto/</a>
- 2. For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



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